Thermal evaporation & RF sputtering system

Manufacturer: Kurt. J. Lesker

Model: PVD75

Serial Number: PTN103000

Descriptions

The Lesker PVD 75 Deposition System provides both thermal and RF sputtering deposition of metal and non-metal films. Three thermal sources by DC power supply and a single RF sputtering source are housed in the process chamber. The system can process samples up to 8" in diameter. Materials approved include: Al, Ag, Au, Cu, Cr, Fe, Mg, SiO₂, ITO, etc. The system features recipe control for efficient use.

Specifications

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Process chamber	Viewport and replaceable deposition shield
	Appropriate pumping, process, gauging and instrumentation ports
Vacuum pumping	•260 l/s speed control compound turbo pump
	• 5.7 cfm oil-sealed mechanical roughing pump and foreline valve
	Foreline trap, mist eliminator, roughing valve, and roughing
	hardware (when applicable)
	Pneumatically actuated vent valve
Vacuum gauging	Wide range vacuum gauge reads from atmosphere to 10 ⁻¹⁰ Torr
Water distribution manifold	Manual shut off valves
	Interlocked flow switches to critical components
	Cryopump compressor requires separate water connection
	• 1" NPT connections (inlet and outlet)
Power distribution	• Single service drop (208/220VAC, 50/60Hz, single phase, 3-wire,
	30 Amps based on configuration)
	Component wiring is routed to a centralized power distribution
	panel
	EMO protection
	• Isolation transformer provides safe operation for sputtering while
	substrate heating
	Appropriate safety interlocks
Magnetron sputtering source	• A Torus magnetron sputter cathode, mounted to an adjustable 3/4"
	tube
	O-ring sealed compression fittings to adjust source-to-substrate
	distance
	Pneumatic source shutter
	KJLC 300W RF power supply with automatic matching
	network
Thermal evaporation sources	Three source assembly with water cooled high current
	feedthroughs (for sequential deposition)
	• DC power supply, 3.3V at 375A max

	• 3 position source switch
	A single (one) pneumatically actuated shutter covers all sources
	Cross contamination shielding
Substrate	• Include variable speed, motor driven rotating platen (up to 20 rpm)
	for primary rotation of the substrate
	Substrate water Cooling platen
Upstream Pressure Control	Two MKS 1179 flow controllers, all cables, and PID upstream
	pressure control electronics
	MKS 626A Baratron 100 mTorr pressure transducer
	System vent and purge pressure regulators
	Pumping speed is regulated by the speed control turbo
Film Thickness Control	PCI Card for interfacing with up to 4 crystal sensors
	One standard crystal sensor (located near the substrate)
Basic Computer Control	PC-based control system (Windows XP)
	KJLC "C-Ware" Visual Basic based software
	Rack mounted PC, touch-screen monitor, flip up keyboard with
	touch pad

